



HPUV Seminar Sweden – Thursday 10 October 2019 Chalmers University of Technology, Gothenburg

09:30	Registration
09:55	Introduction
10:00	<p>State-of-the-Art in Spectrophotometry</p> <ul style="list-style-type: none"> • Short Introduction OMT Solutions • Overview of accessories for Thin Film Analysis <ul style="list-style-type: none"> - Measuring both Reflectance and Transmittance at 8° AOI with the same measurement spot - Thin film analysis by Variable Angle Spectroscopy (VAS) • Microscope accessories <ul style="list-style-type: none"> - Measuring reflectance and transmittance with a 20 micron spot size • Measuring extremely large samples • Measuring reflectance at high sample temperatures • Connecting to a reflectance set-up in external vacuum chambers
10:35	<p>Tools for Thin Film Analysis</p> <ul style="list-style-type: none"> • Available accessories • Problems and solutions in variable angle spectroscopy • ARTA versus TAMS • TAMS (Total Absolute Measurement System) in detail • Measuring angular resolved scattering of textured coatings
11:25	Break
11:40	<p>How to perform BRDF/BTDF measurements</p> <ul style="list-style-type: none"> • Geometrical Considerations and Nomenclature • Setup using the ARTA • Setup using TAMS • Various case studies
12:15	<p>Measuring diffusing and textured samples</p> <ul style="list-style-type: none"> • Total, Diffuse and Haze measurements • Problems and solutions in transmittance measurements of diffusing and textured samples • Standard 150 mm sphere versus UL270 (270 mm sphere accessory) • An upward looking 150 sphere accessory with 4 measurement modes and controlled sample temperature • Variable Angle Spectroscopy on diffusing and textured samples
13:00	Lunch
14:00	Presentation of line of High Performance UV/VIS-NIR spectrophotometers from PerkinElmer
14:30	Open discussion, Q&A for application support
16:00	Close